

Electrochemical memory for energy efficient computing

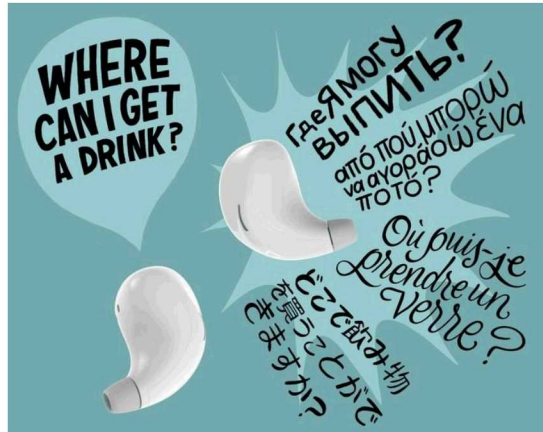


PRESENTED BY

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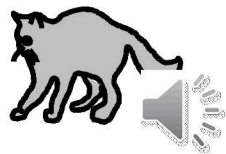
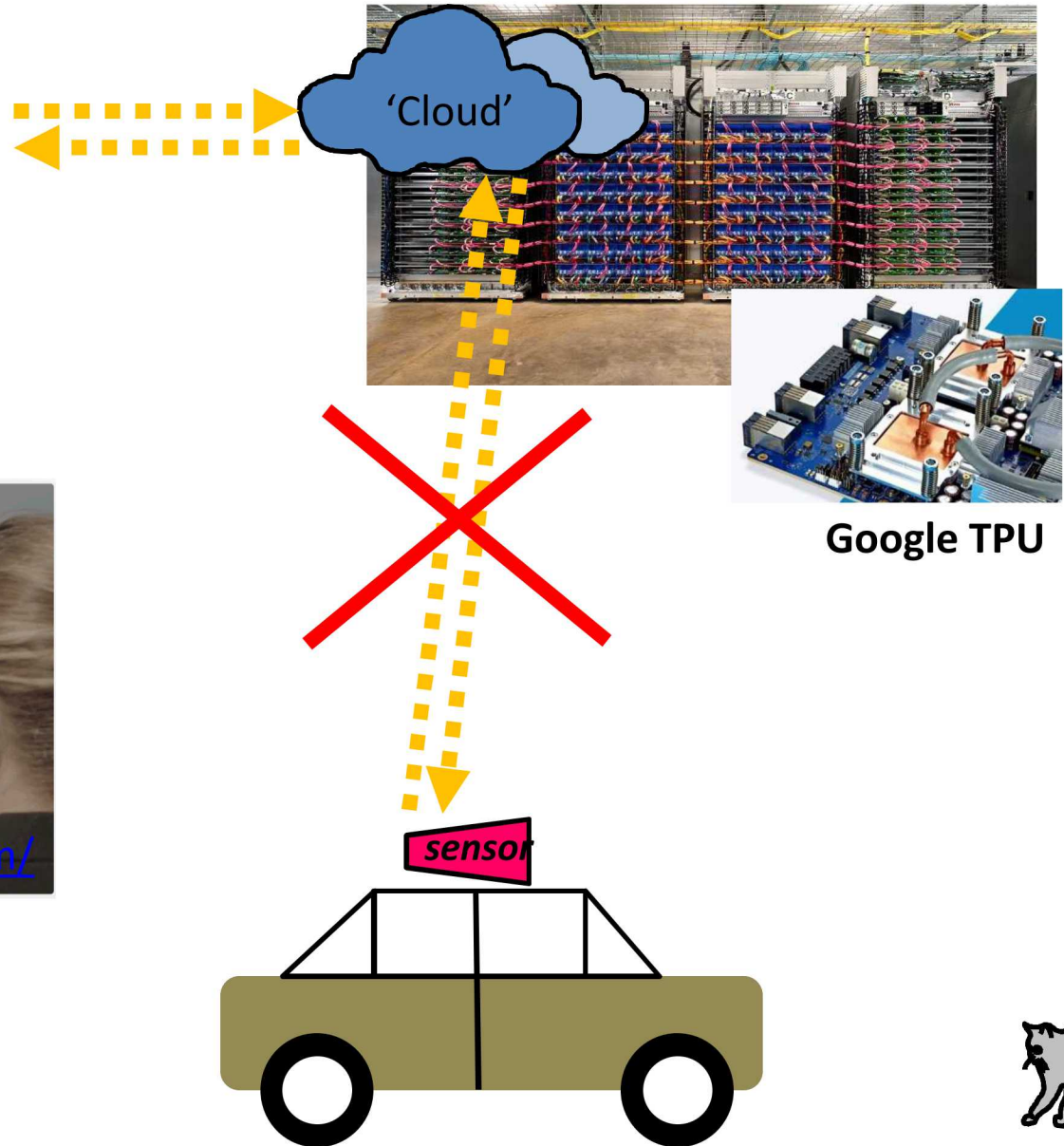
The need for low power computing



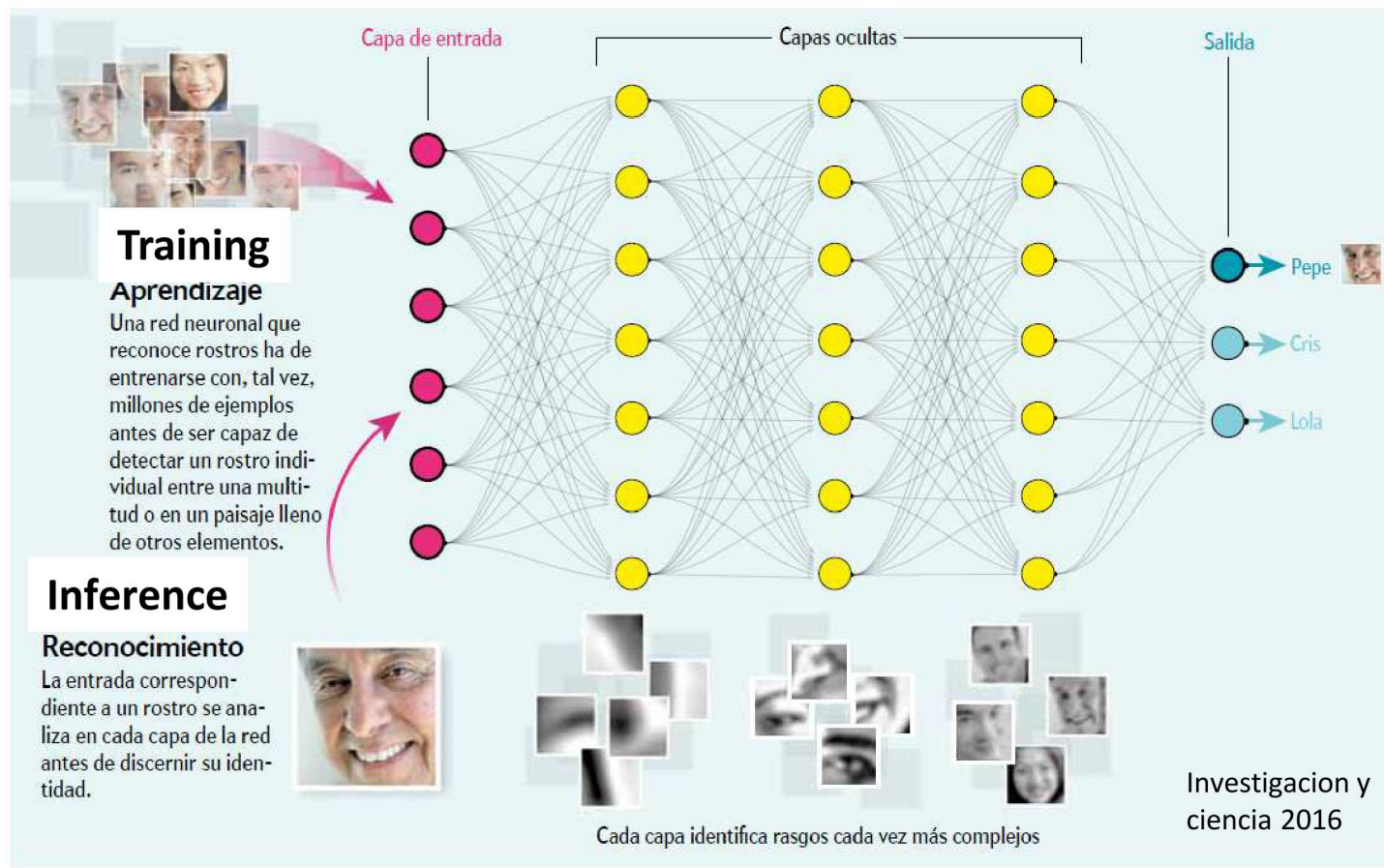
<https://www.wsj.com/articles/can-smart-earbuds-instantly-translate-foreign-speech-1530279191>



<https://www.waverlylabs.com/>



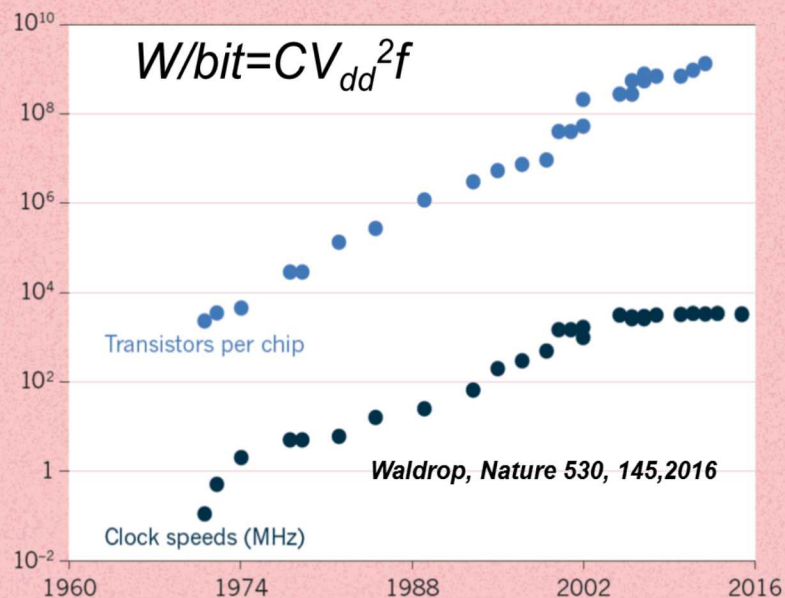
Artificial neural networks and deep learning



$$\begin{bmatrix} y_1 \\ \vdots \\ y_m \end{bmatrix} = \begin{bmatrix} w_{1,1} & \cdots & w_{1,n} \\ \vdots & \ddots & \vdots \\ w_{m,1} & \cdots & w_{m,n} \end{bmatrix} \begin{bmatrix} x_1 \\ \vdots \\ x_n \end{bmatrix}$$

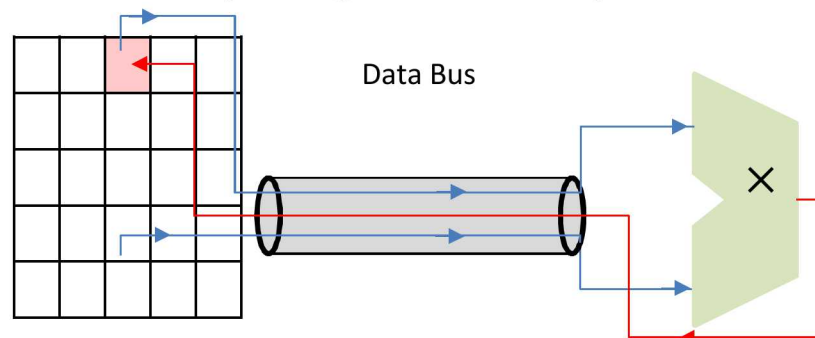


Excess power limits IC performance

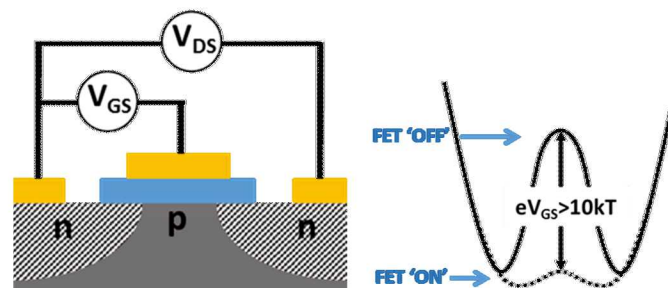


Year

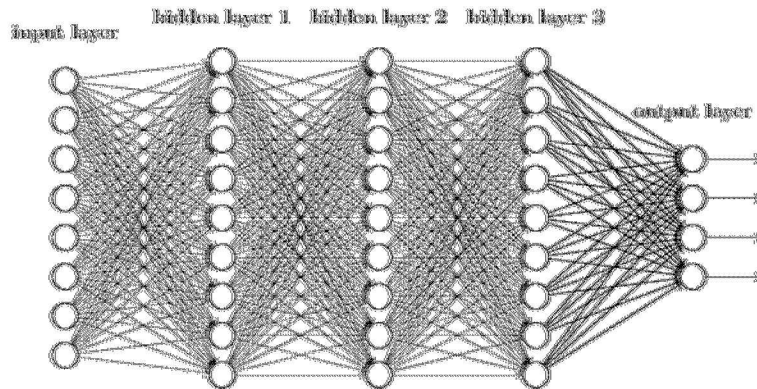
1) Data transfer logic<->memory



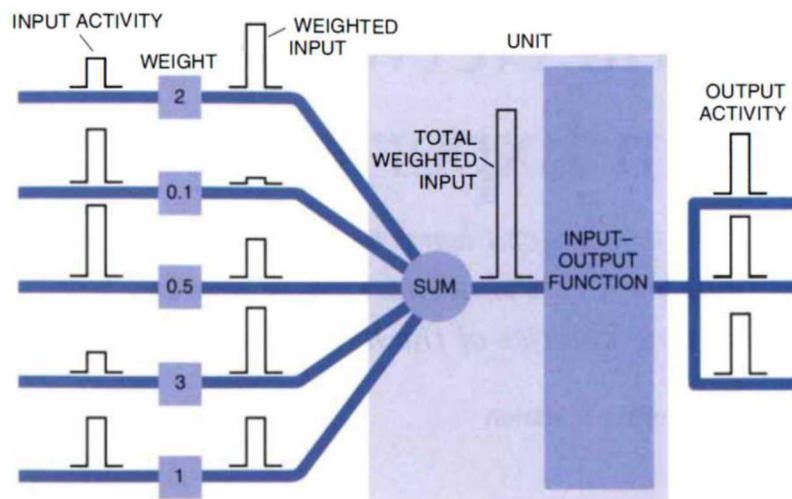
2) High switching voltage



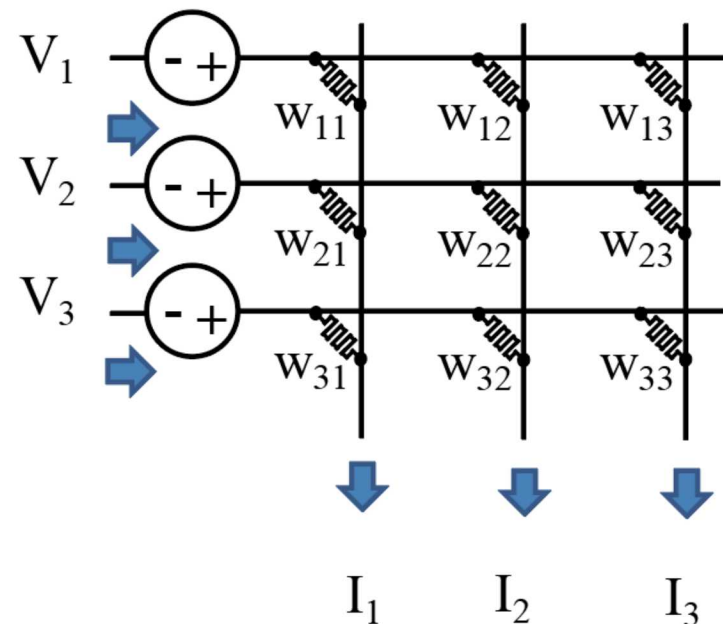
Analog implementations of neural networks



$$\begin{bmatrix} y_1 \\ \vdots \\ y_m \end{bmatrix} = \begin{bmatrix} w_{1,1} & \cdots & w_{1,n} \\ \vdots & \ddots & \vdots \\ w_{m,1} & \cdots & w_{m,n} \end{bmatrix} \begin{bmatrix} x_1 \\ \vdots \\ x_n \end{bmatrix}$$



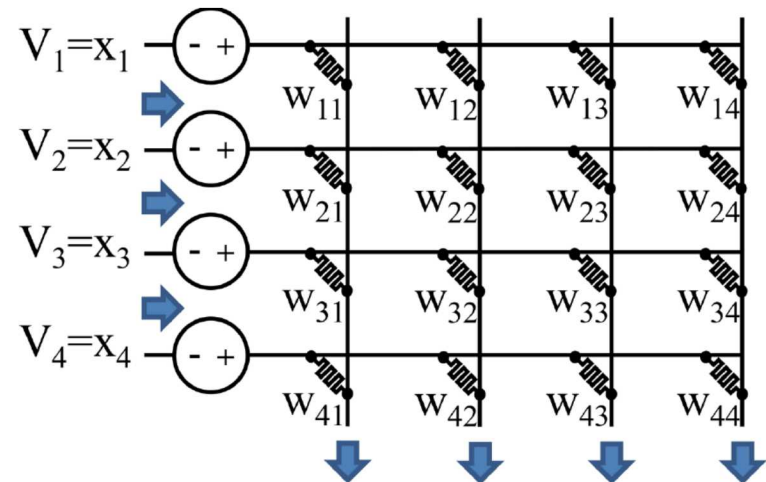
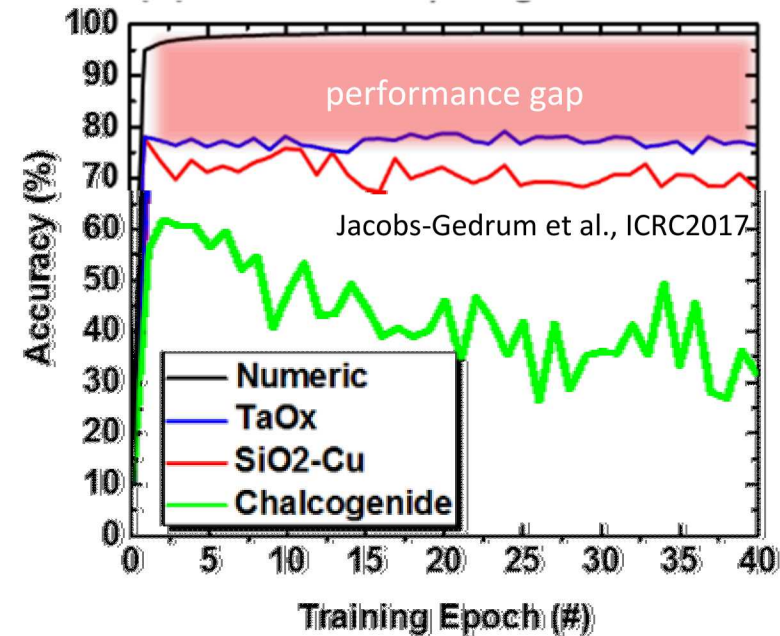
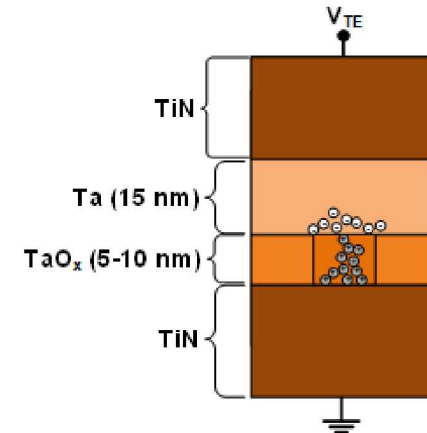
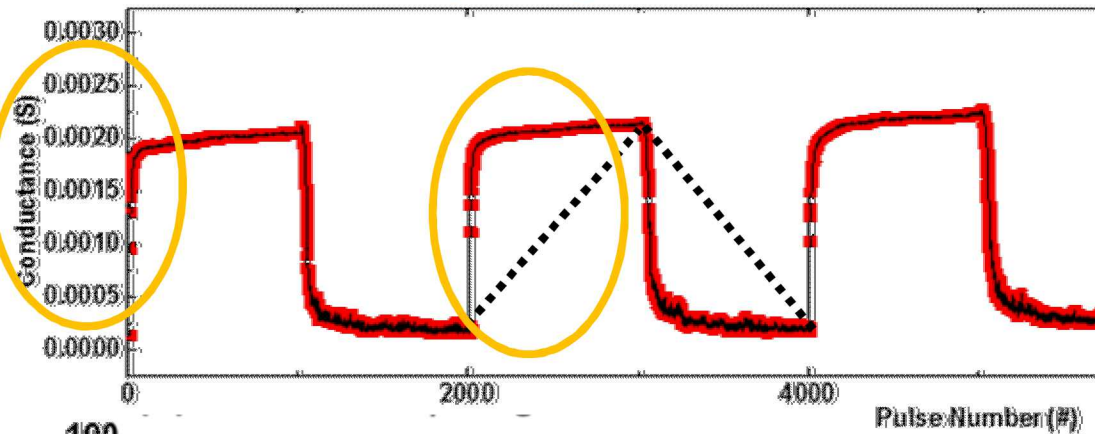
Hinton, Scientific American 1993



$$I_1 = V_1 W_{11} + V_2 W_{21} + V_3 W_{31}$$



Non-linearity, high conductance limit accuracy, scaling

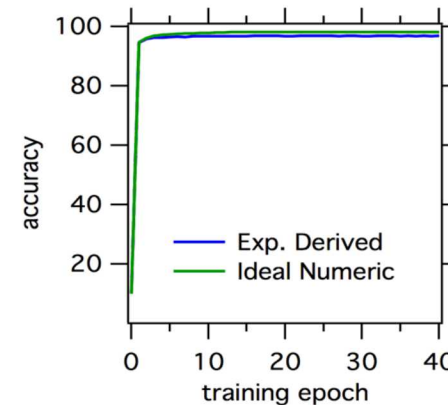
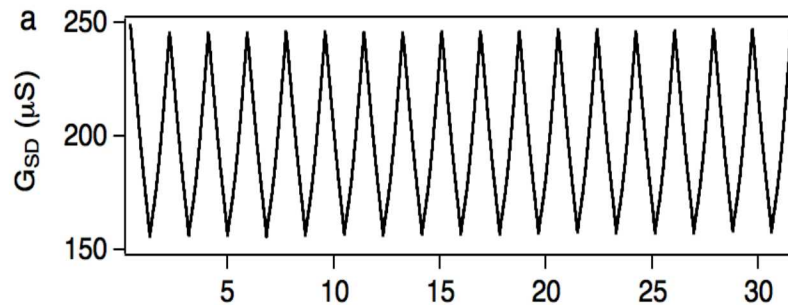
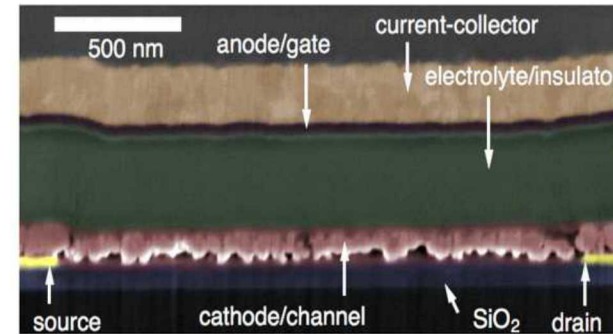
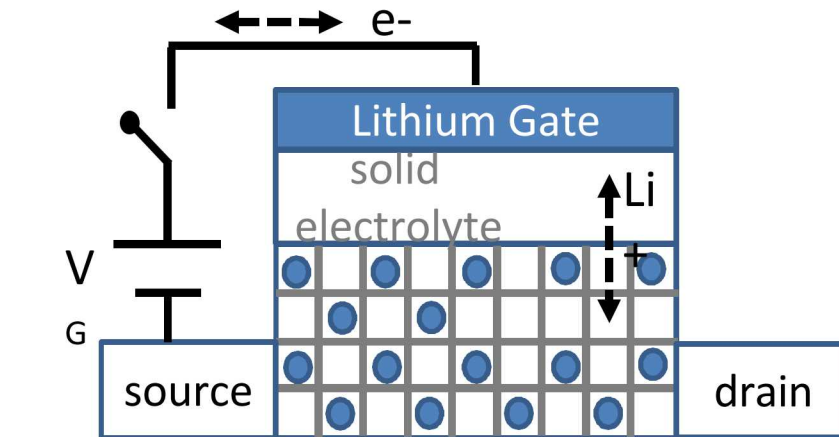


7 5 3 5 3
5 5 9 0 6
3 5 2 0 0

Data set	# Training Examples	# Test Examples	Network Size
MNIST Large Digits	60,000	10,000	784×300×10



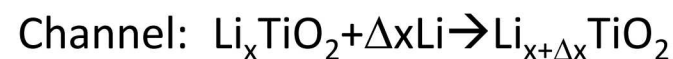
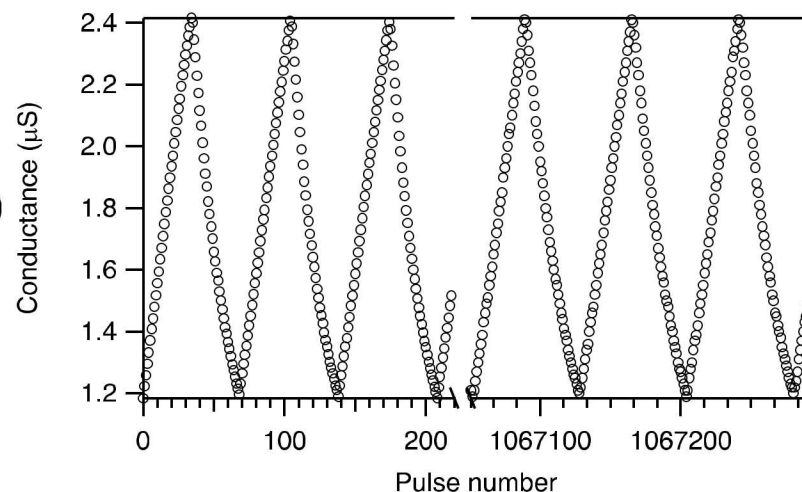
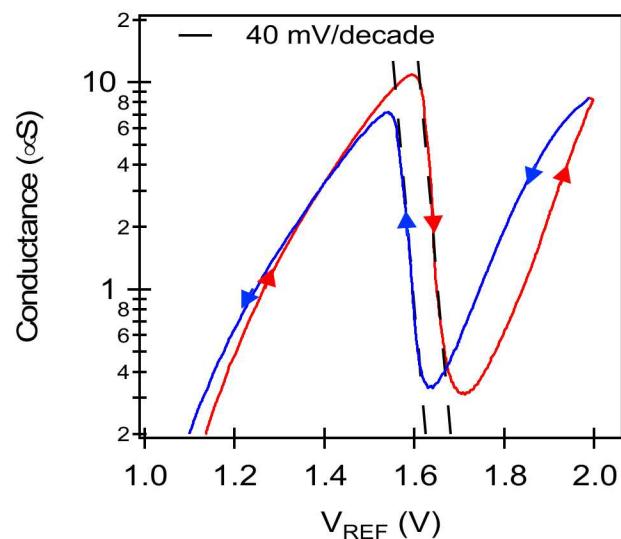
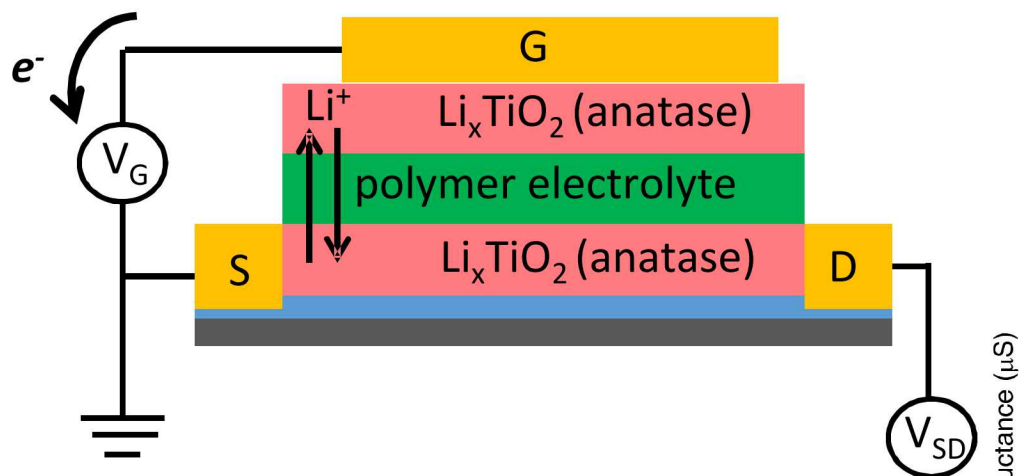
Ion-insertion electrodes for neuromorphic computing



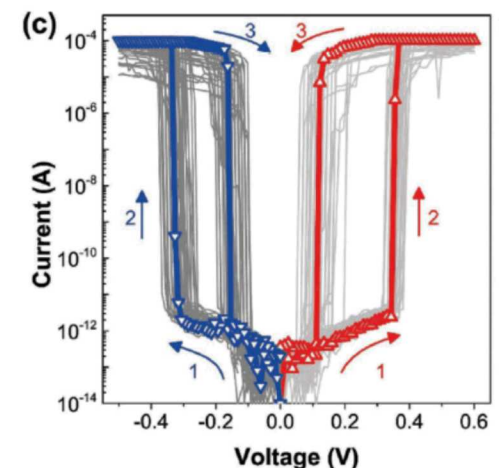
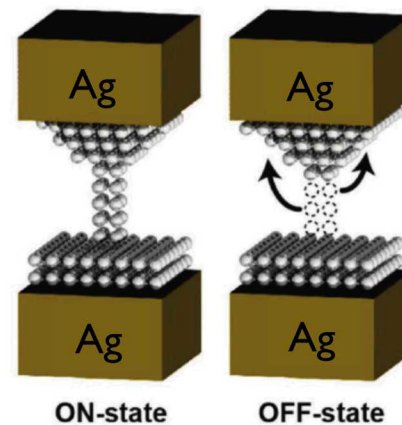
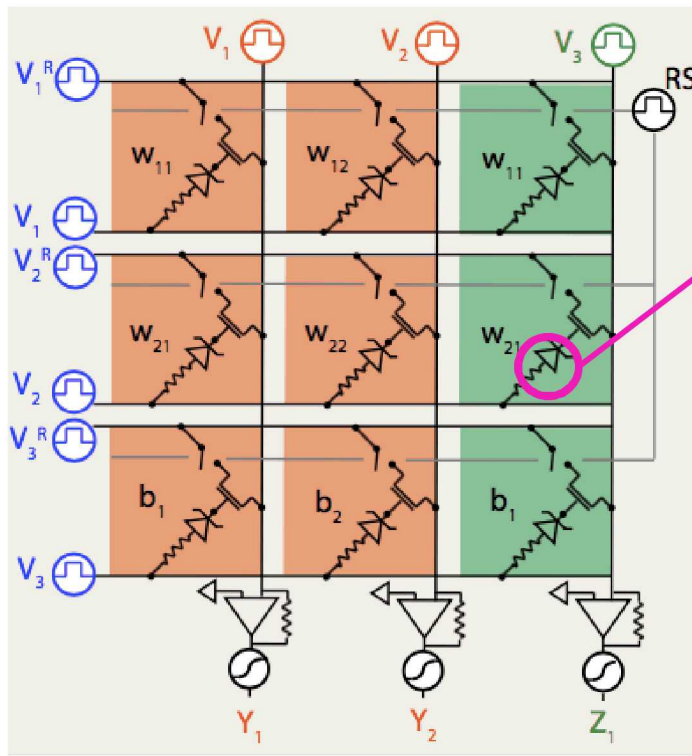
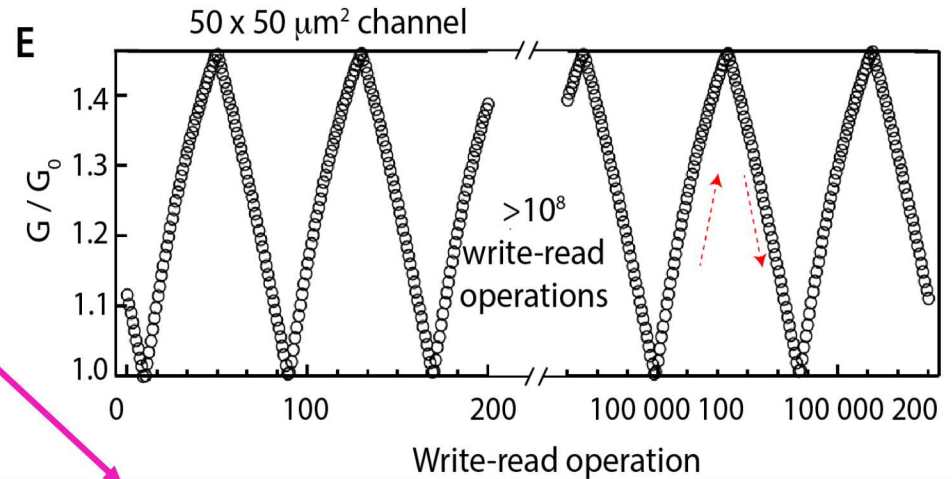
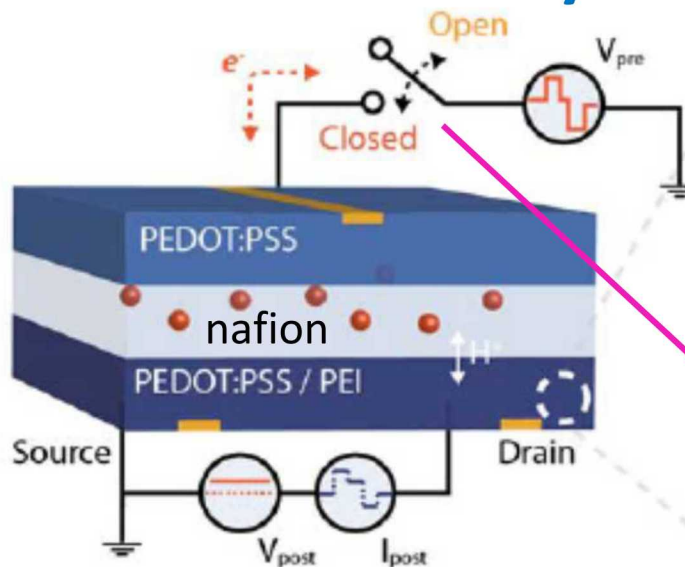
E. J. Fuller, F. El Gabaly, F. Léonard, S. Agarwal, S. J. Plimpton, R. B. Jacobs-Gedrim, C. D. James, M. J. Marinella, A. A. Talin, Adv. Mat., 29, 1604310, 2017



$\text{Li}_x\text{TiO}_2\text{-Li}_x\text{TiO}_2$ symmetric redox transistor

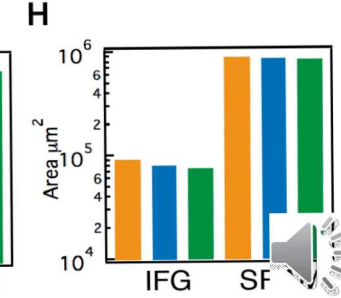
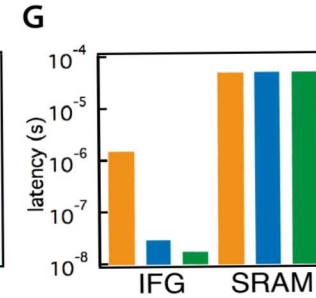
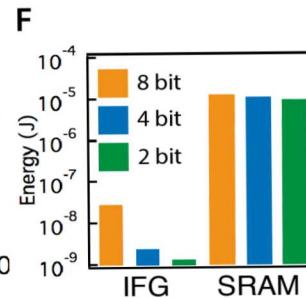
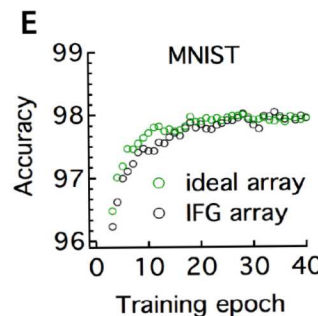
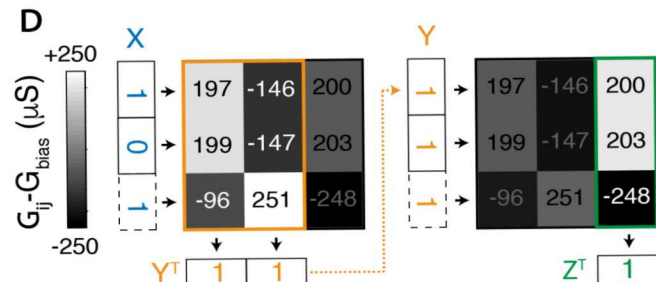
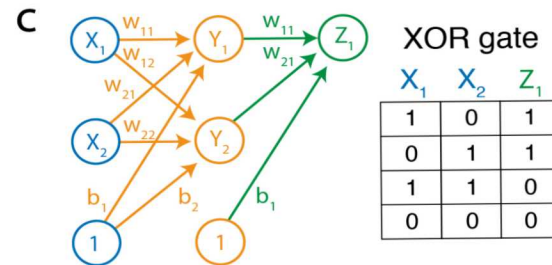
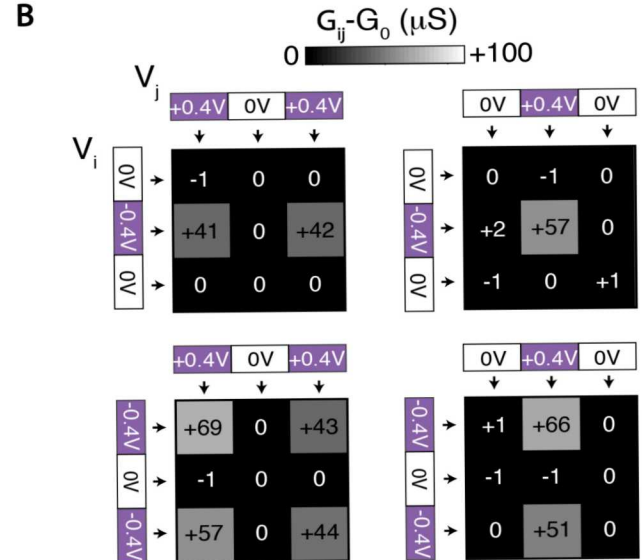


Polymer redox transistor



Y.B. van de Burgt, E. Lubberman, E.J. Fuller, S.T. Keene, G.C. Faria, S. Agarwal, M.J. Marinella, A.A. Talin*, A. Salleo*, *Nature Materials* 16, 414, 2017

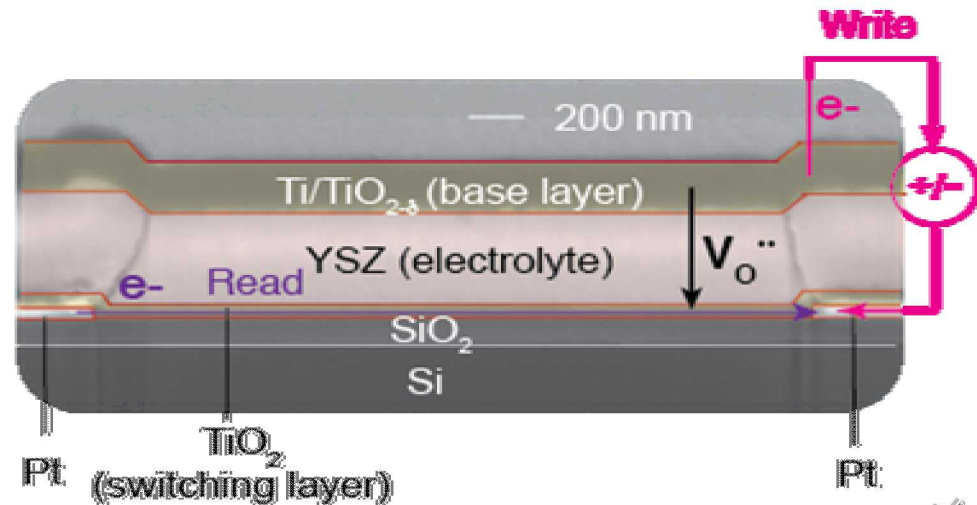
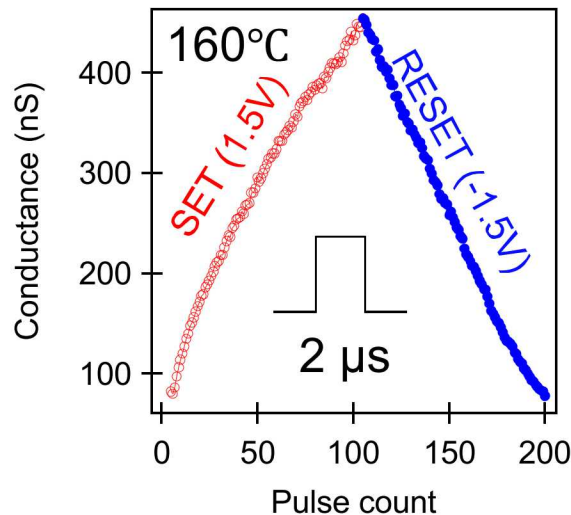
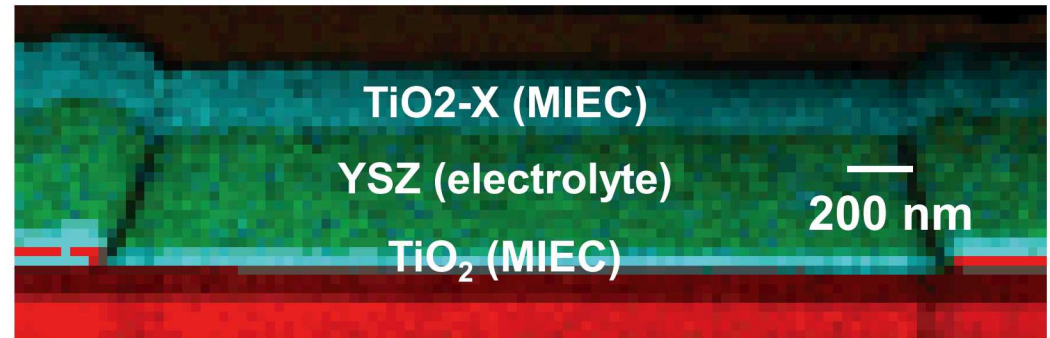
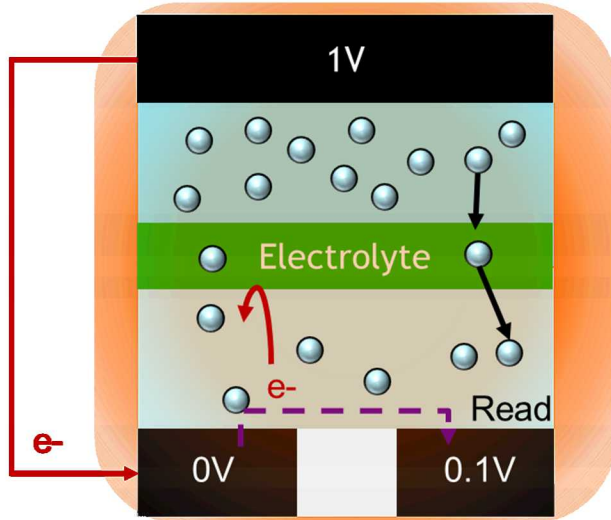
E. J. Fuller, S. T. Keene, A. Melianas, Z. Wang, S. Agarwal, Y. Li, Y. Tuchman, James, M. J. Marinella, J. J. Yang, A. Salleo, A. A. Talin, *Science* 364, 570, (2015)



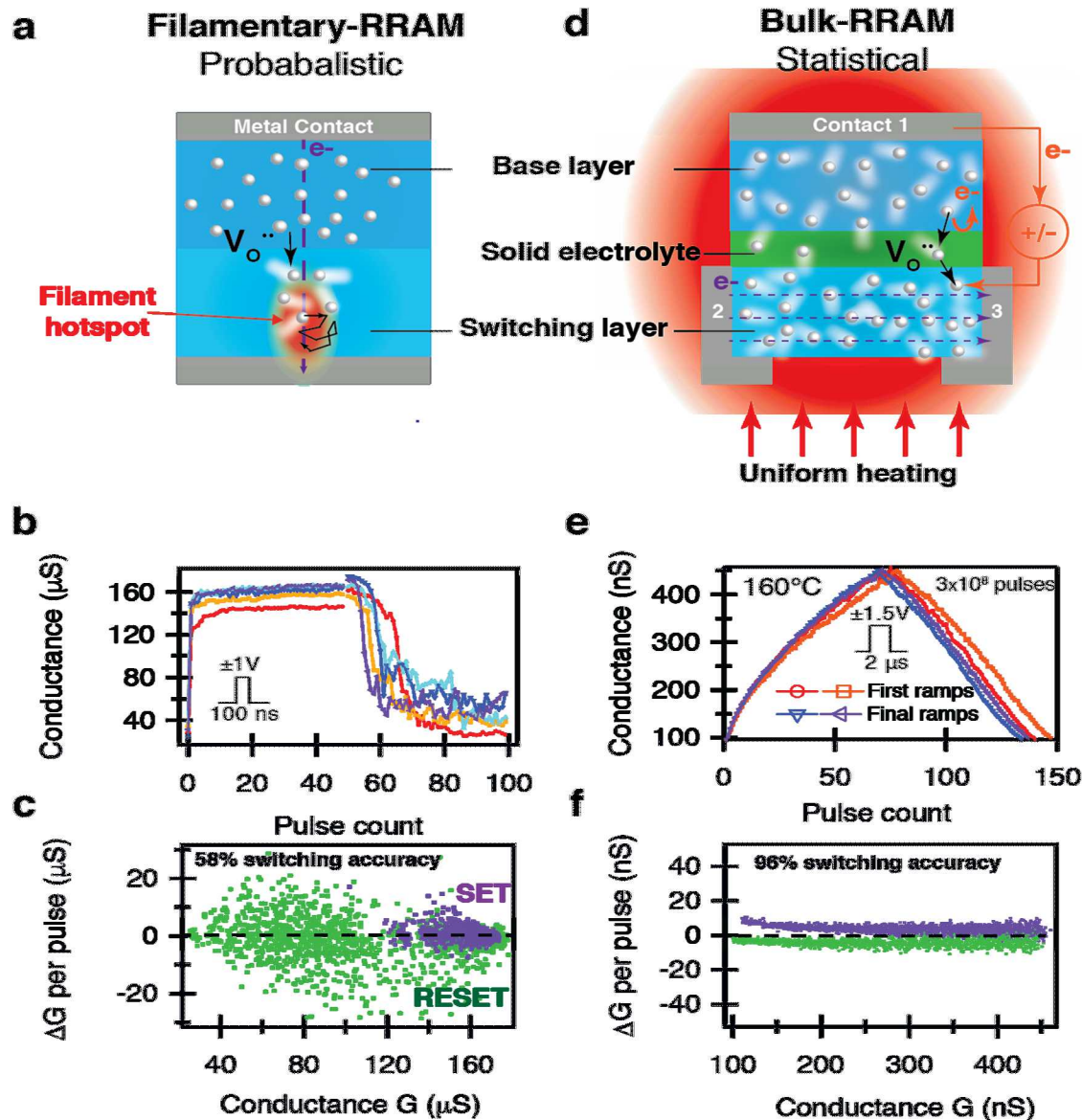
E. J. Fuller, S. T. Keene, A. Melianas, Z. Wang, S. Agarwal, Y. Li, Y. Tuchman, C. D. James, M. J. Marinella, J. J. Yang, A. Salleo, A. A. Talin, *Science* 364, 570, (2019).

Oxygen vacancy redox transistor (ECRAM, bulk-ReRAM)

Y. Li, E. J. Fuller, J. D. Sugar, S. Yoo, D. S. Ashby, C. H. Bennett, R. D. Horton,
M. S. Bartsch, M. J. Marinella, W. D. Lu, A. A. Talin, Adv. Mat., accepted)



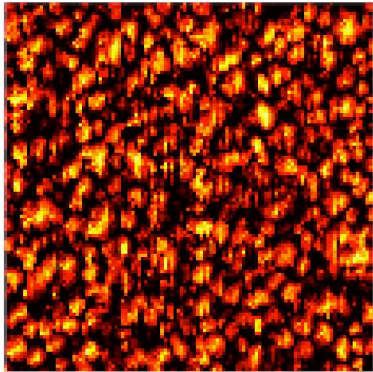
Deterministic switching through bulk vacancy control



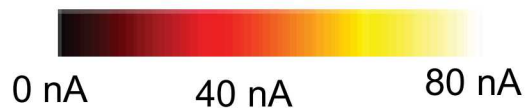
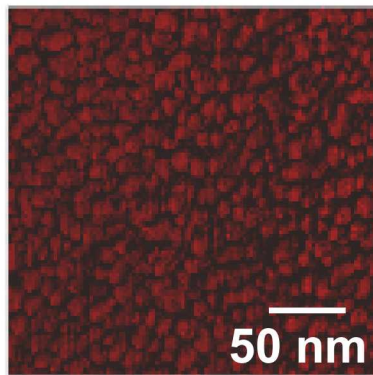
Conductive-AFM shows uniform switching

Y. Li, E. J. Fuller, J. D. Sugar, S. Yoo, D. S. Ashby, C. H. Bennett, R. D. Horton, M. S. Bartsch, M. J. Marinella, W. D. Lu, A. A. Talin, Adv. Mat., in revision)

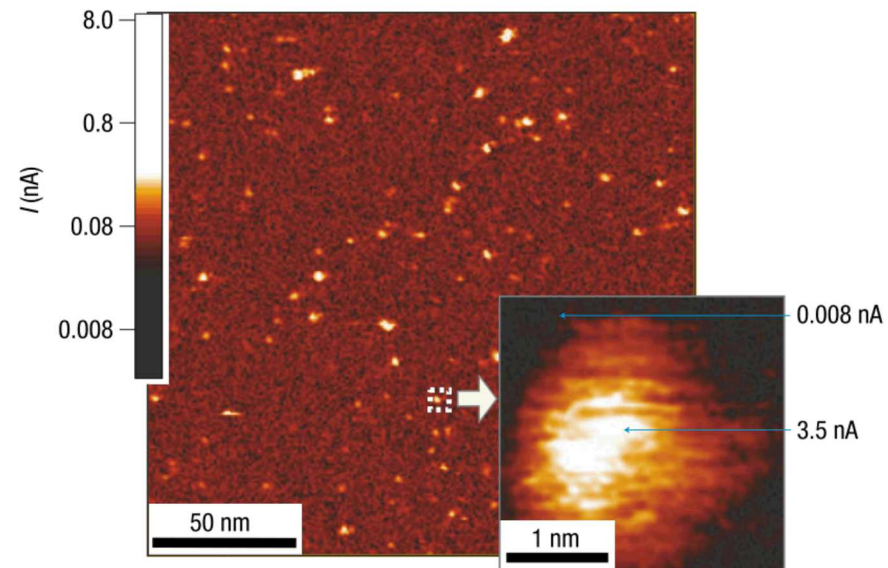
High-conductance state



Low-conductance state



Filamentary-RRAM shows conductive filaments

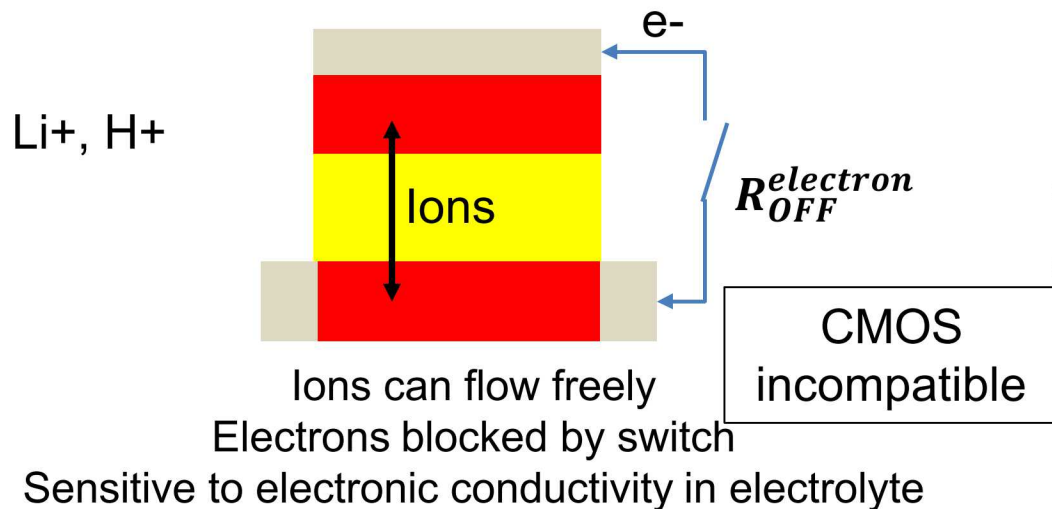


Szot et al. *Nat. Mater.* 5, 312 (2006)

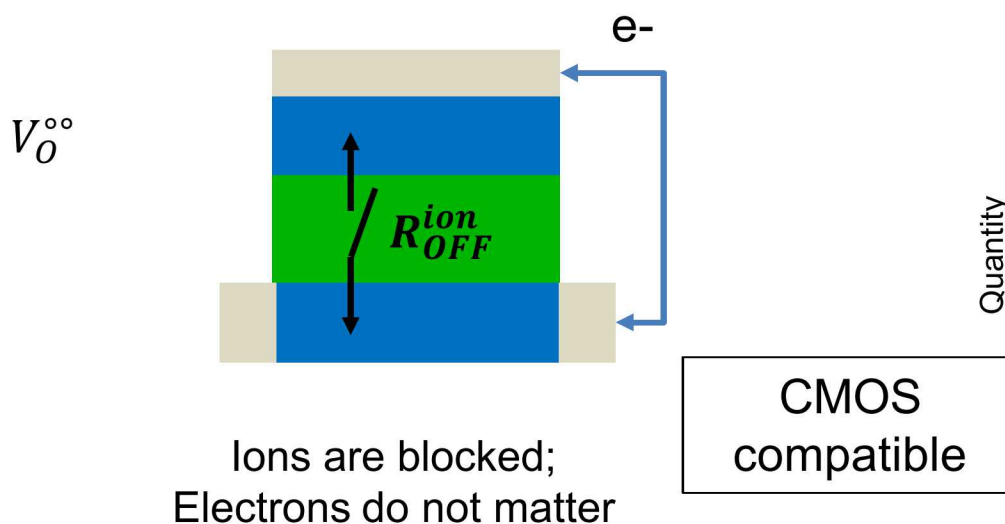
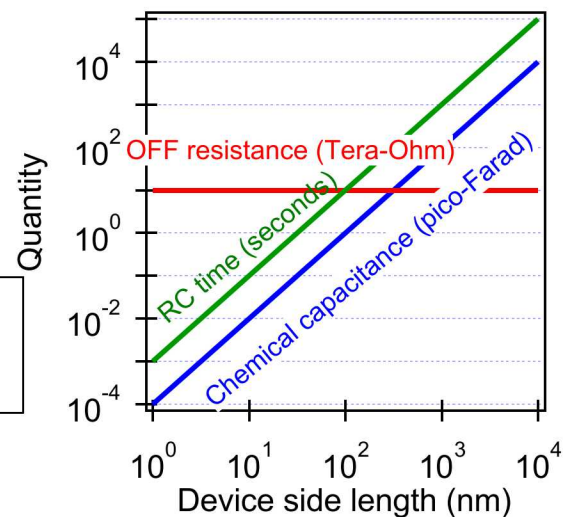


Retention time of Li, H vs O ECRAM

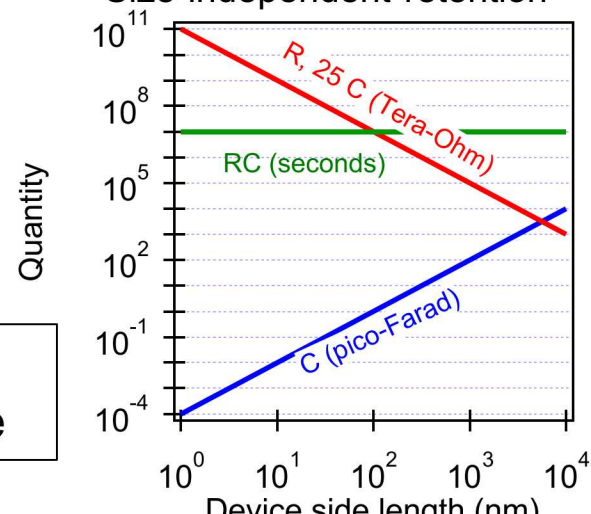
Switching requires movement of both electron & ion
Retention requires one or both be blocked



Poor retention for at smaller sizes



Size-independent retention



Contributors:

SNL

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